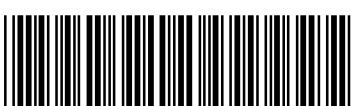


<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10763817	TANAKA, MIKIHIRO
	<b>Examiner</b>	<b>Art Unit</b>
	NAM HUYNH	2617

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
455	450, 451, 452.2, 453, 454	3/14/08	NTH
370	342, 348	3/14/08	NTH

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
See EAST search notes.	3/14/08	NTH
Received search help from 370 Examiner Ngo Nguyen	1/15/2009	NTH
See EAST search notes.	1/16/2009	NTH

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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